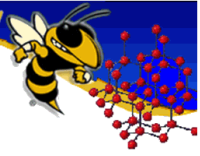


## Lecture 9

# Photogeneration, Absorption, and Nonequilibrium

**Reading:**

**Pierret 3.3-3.4**

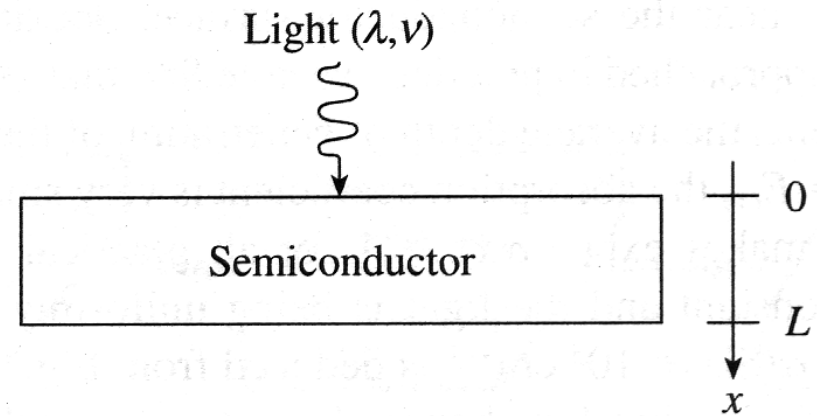
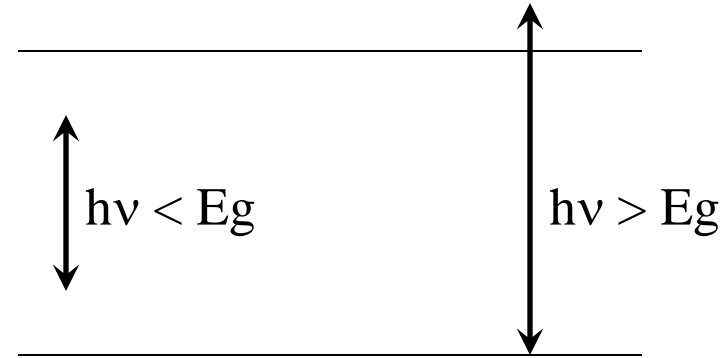


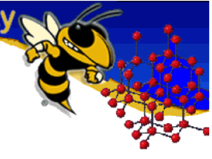
# Photogeneration

Light with photon energy,  $h\nu < E_g$  is not easily absorbed. A convenient expression for the energy of light is  $E = 1.24/\lambda$  where  $\lambda$  is the wavelength of the light in  $\mu\text{m}$ .

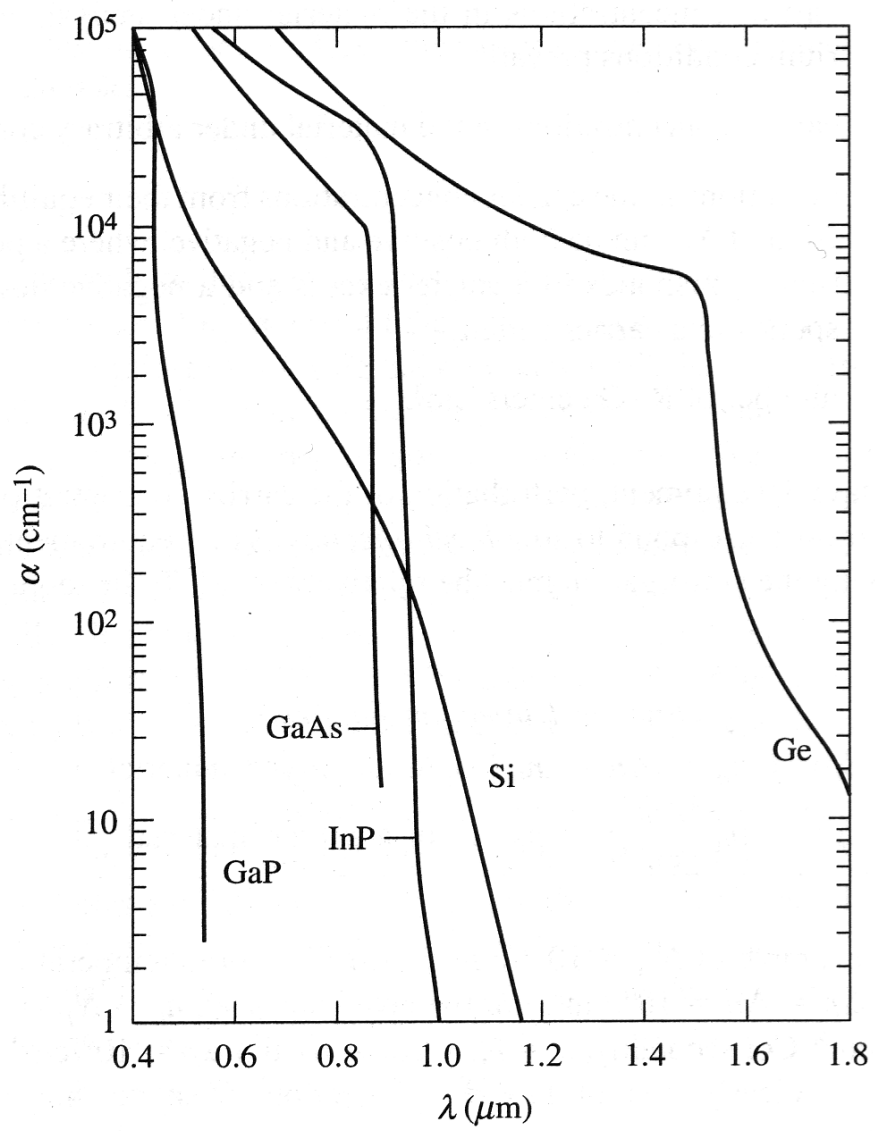
Light with energy,  $h\nu > E_g$  is absorbed with the “unabsorbed” light intensity as a function of depth into the semiconductor is  $I(x) = I_0 e^{-\alpha x}$

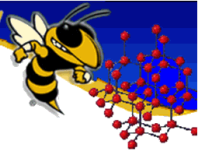
where  $I_0$  is the initial light intensity,  $x$  is distance and  $\alpha$  is the absorption coefficient [1/cm].





# Photogeneration





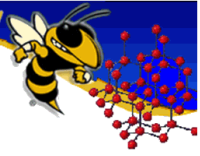
# Photogeneration

Each Photon with energy greater than  $E_g$  can result in one electron hole pair. Thus, we can say,

$$\left. \frac{\partial n}{\partial t} \right|_{\text{Light}} = \left. \frac{\partial p}{\partial t} \right|_{\text{Light}} = G_L(x, \lambda) \quad \text{where } G_L(x, \lambda) = G_{L0} e^{-\alpha x} \quad \# / (cm^3 - Sec)$$

If  $\alpha$  is small (near bandgap light), the generation profile can be approximately constant.

If  $\alpha$  is large (light with energy  $\gg$  bandgap), the generation profile can be approximated as at the surface.



## Important Nomenclature

$n_0, p_0$	...	carrier concentrations in the material under analysis when equilibrium conditions prevail.
$n, p$	...	carrier concentrations in the material under arbitrary conditions.
$\Delta n \equiv n - n_0$	...	deviations in the carrier concentrations from their equilibrium values.
$\Delta p \equiv p - p_0$		$\Delta n$ and $\Delta p$ can be both positive and negative, where a positive deviation corresponds to a carrier excess and a negative deviation corresponds to a carrier deficit.
$N_T$	...	number of R-G centers/cm <sup>3</sup> .

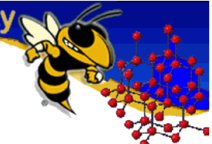
$$n = \Delta n + n_0 \text{ and } p = \Delta p + p_0$$

In Non-equilibrium,  $np$  does not equal  $n_i^2$

### Low Level Injection

$\Delta p = \Delta n \ll n_0$  and  $n \sim n_0$  in n-type material

$\Delta p = \Delta n \ll p_0$  and  $p \sim p_0$  in p-type material

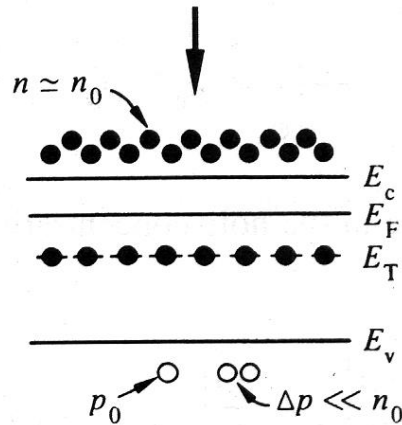
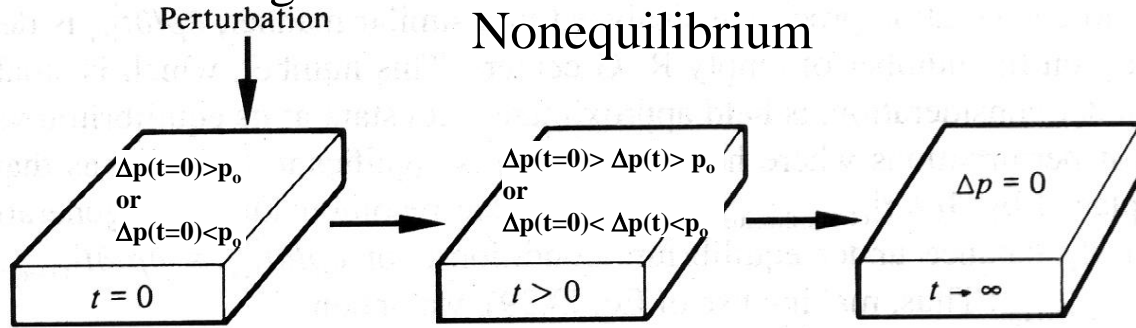


# Carrier Concentrations after a "Perturbation"

Steady State if  
perturbation has been  
applied for a long time

Non-Steady State,  
Nonequilibrium

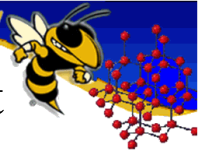
Equilibrium



$\Delta p$  can be  $\gg p_0$

If  $\Delta p \gg p_0$ ,  $p \sim \Delta p$

After the carrier concentrations are perturbed by some stimulus (leftmost case) and the stimulus is removed (center case) the material relaxes back toward its equilibrium carrier concentrations.



# Material Response to “Non-Equilibrium”: Relaxation Concept

Consider a case when the hole concentration in an n-type sample is not in equilibrium, i.e.,  $pn$  does NOT equal  $n_i^2$

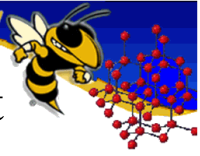
$$\left. \frac{\partial p}{\partial t} \right|_{thermal \ R-G} = -\frac{\Delta p}{\tau_p} \quad \text{where} \quad \tau_p = \frac{1}{c_p N_T}$$

*where  $\tau_p$  is the minority carrier lifetime*

*$c_p$  is a proportionality constant*

*$N_T$  is the "trap" concentration*

- The minority carrier lifetime is the average time a minority carrier can survive in a large ensemble of majority carriers.
- If  $\Delta p$  is negative  $\rightarrow$  Generation or an increase in carriers with time.
- If  $\Delta p$  is positive  $\rightarrow$  Recombination or a decrease in carriers with time.
- Either way the system “tries to reach equilibrium”
- The rate of relaxation depends on how far away from equilibrium we are.



# Material Response to "Non-Equilibrium": Relaxation Concept

Likewise when the electron concentration in an p-type sample is not in equilibrium, i.e.,  $pn$  does NOT equal  $n_i^2$

$$\left. \frac{\partial n}{\partial t} \right|_{\text{thermal R-G}} = -\frac{\Delta n}{\tau_n} \quad \leftarrow \quad \text{where} \quad \tau_n = \frac{1}{c_n N_T}$$

*where  $\tau_n$  is the minority carrier lifetime*

*$c_n$  is a different proportionality constant*

*$N_T$  is the "trap" concentration*

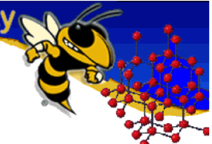
More generally for any doping case:

$$\left. \frac{\partial n}{\partial t} \right|_{\text{thermal R-G}} = \left. \frac{\partial p}{\partial t} \right|_{\text{thermal R-G}} = \frac{n_i^2 - np}{\tau_p(n + n_1) + \tau_n(p + p_1)} \quad \left. \vphantom{\frac{\partial n}{\partial t}} \right\} \text{Same unit as above}$$

where...

$$n_1 \equiv n_i e^{(E_T - E_i)/kT} \quad \text{and} \quad p_1 \equiv n_i e^{(E_i - E_T)/kT}$$





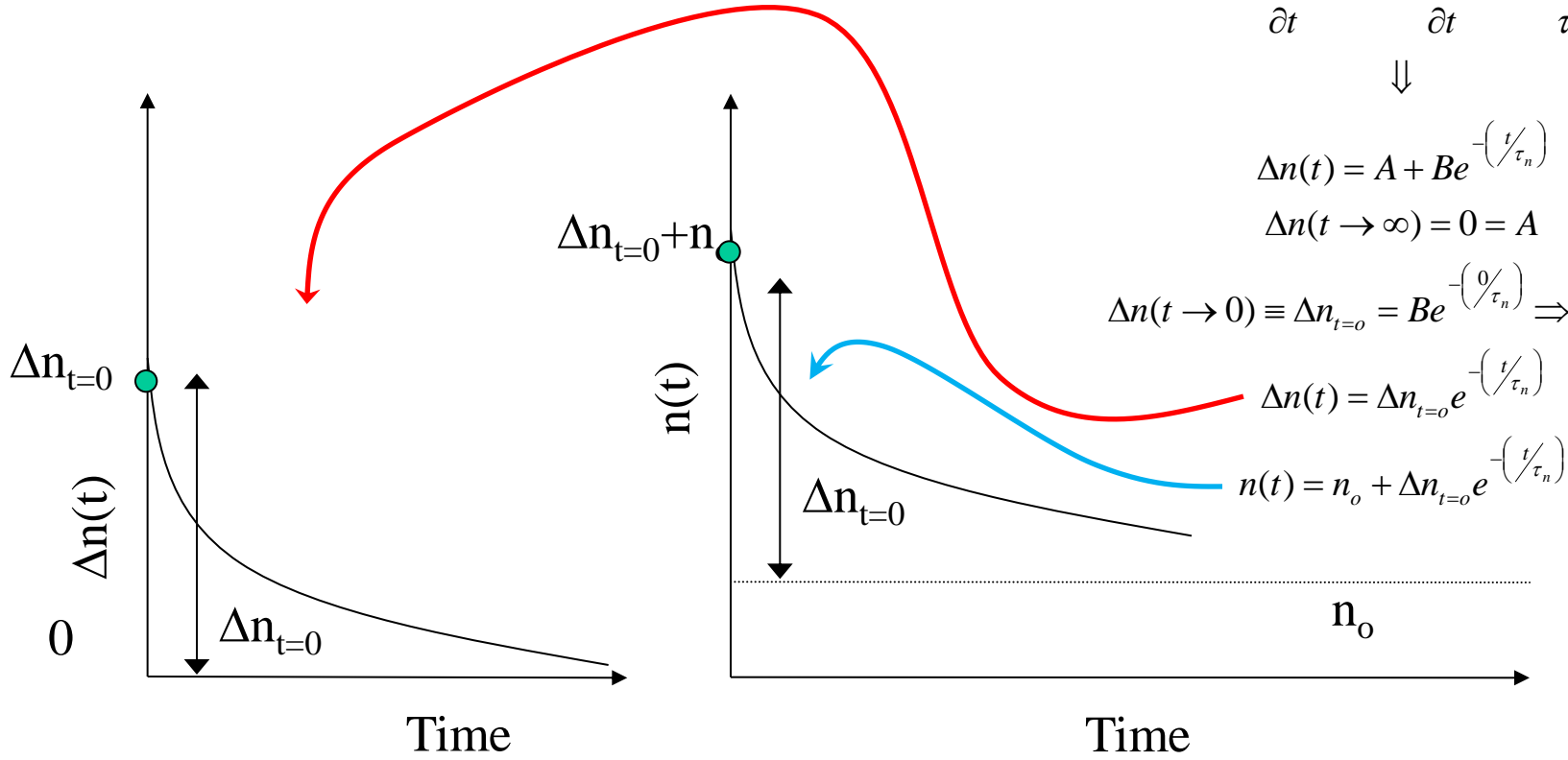
Example: After a long time on, a light is switched off

$$\frac{\partial n}{\partial t} = -\frac{\Delta n}{\tau_n} \quad \text{has a solution}$$

$$n(t) = n_o + \underbrace{\Delta n_o e^{-\left(\frac{t}{\tau_n}\right)}}_{\Delta n(t)} \quad \text{where } \Delta n_o = \text{initial excess electron concentration}$$

$$\frac{\partial n}{\partial t} = -\frac{\Delta n}{\tau_n}$$

$$\frac{\partial(n_o + \Delta n)}{\partial t} = \frac{\partial(\Delta n)}{\partial t} = -\frac{\Delta n}{\tau_n}$$



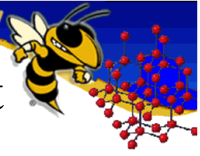
$$\Delta n(t) = A + B e^{-\left(\frac{t}{\tau_n}\right)}$$

$$\Delta n(t \rightarrow \infty) = 0 = A$$

$$\Delta n(t \rightarrow 0) \equiv \Delta n_{t=0} = B e^{-\left(\frac{0}{\tau_n}\right)} \Rightarrow \Delta n_o = B$$

$$\Delta n(t) = \Delta n_{t=0} e^{-\left(\frac{t}{\tau_n}\right)}$$

$$n(t) = n_o + \Delta n_{t=0} e^{-\left(\frac{t}{\tau_n}\right)}$$



# Material Response to “Non-Equilibrium”: Relaxation Concept

Carrier Relaxation can also be achieved through Direct recombination

Given:  $\Delta n = \Delta p$ ,  $n = n_o + \Delta n$ ,  $p = p_o + \Delta p$

Low Level Injection  $\implies \Delta n \ll N_a$  and High Level Injection  $\implies \Delta n \gg N_a$

- Recombination Rate,  $R = Bnp$  [# / cm<sup>3</sup> sec.] (depends on number of electrons and holes present)
- In Thermal Equilibrium,

$np = n_i^2$  where  $n_i^2$  is the n-p product due to thermal generation (intrinsic generation)

Recombination rate,  $R = B n_i^2 = G$ , Generation Rate where B is a constant

Under Illumination (Non-thermal equilibrium),  $np \neq n_i^2$

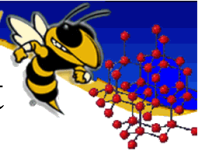
Net Recombination Rate,  $-dn/dt = R - G = B(np - n_i^2)$

but,  $\Delta n = \Delta p$

$$\begin{aligned}
 -dn/dt &= B(np - n_i^2) \\
 &= B((n_o + \Delta n)(p_o + \Delta p) - n_i^2) \\
 &= B(n_o p_o - n_i^2 + \Delta p n_o + \Delta n p_o + \Delta n \Delta p) \\
 &= B\Delta n(0 + n_o + p_o + \Delta n) \\
 &= B\Delta n(n_o + p_o + \Delta n)
 \end{aligned}$$

Thus, using our lifetime definition,

$$\begin{aligned}
 -dn/dt &= -\Delta n / \tau_e \\
 \tau_e &= 1 / (B(n_o + p_o + \Delta n))
 \end{aligned}$$



# Material Response to “Non-Equilibrium”: Relaxation Concept

Carrier Relaxation can also be achieved through Direct recombination

Special cases:

Low Level Injection:  $\Delta n \ll \text{majority carrier density}$

$$\tau_e = 1 / (B(n_o + p_o))$$

and if the material is n-type:

$$\tau_e = 1 / (Bn_o)$$

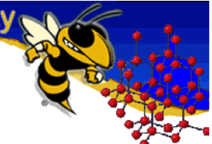
or p-type:

$$\tau_e = 1 / (Bp_o)$$

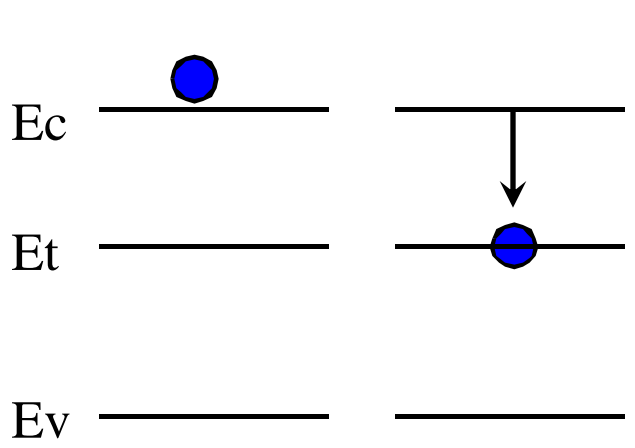
High level injection:  $\Delta n \gg \text{majority carrier density}$

$$\tau_e = 1 / (B\Delta n)$$

Optional



# Electron Capture and Emission



Electron Capture

How many electrons are available for capture

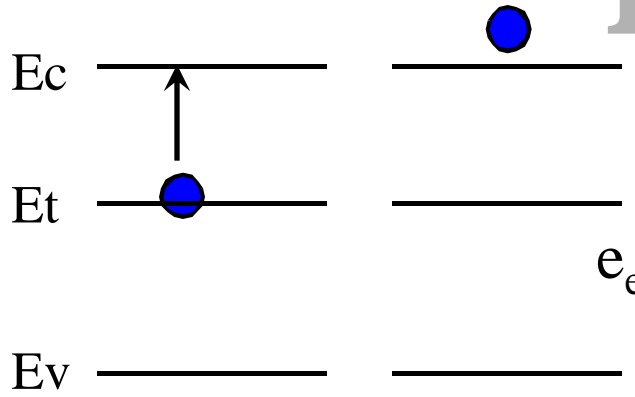
Number of empty defect sites

$$c_e = v_{th,e} \sigma_n n N_t (1-f(E))$$

Electron Capture Rate

Capture cross section: Effective size of the defect. Units of area  
 Thermal velocity: How fast the electrons are moving

Optional

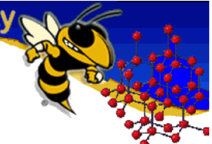


Electron Emission

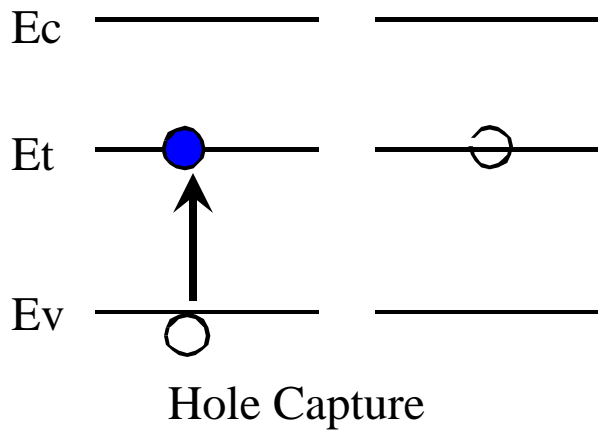
Number of filled defect sites

$$e_e = e_n N_t f(E) \text{ where } e_n = v_{th,e} \sigma_n N_c e^{-(E_c - E_t)/KT}$$

Electron Emission Rate



# Hole Capture and Emission



How many holes are available for capture

Number of filled defect sites

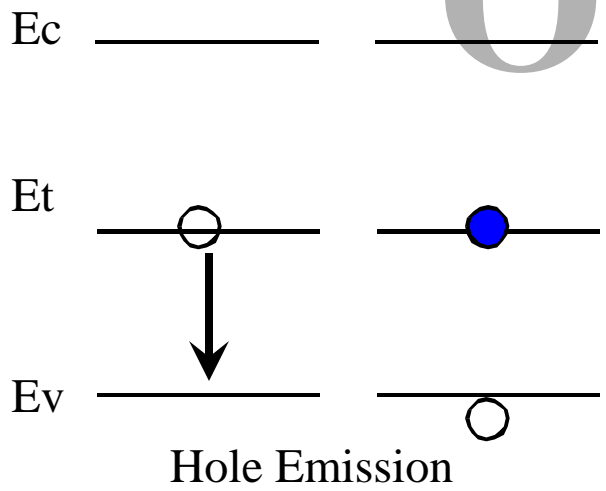
$$c_p = v_{th,p} \sigma_p p N_t f(E)$$

Hole Capture Rate

Thermal velocity: How fast the holes are moving

Capture cross section: Effective size of the defect. Units of area

Optional

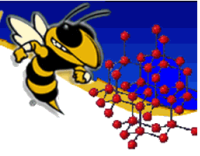


Number of empty defect sites

$$e_p = e_h N_t (1 - f(E))$$

where  $e_h = v_{th,p} \sigma_p N_v e^{-(Et-Ev)/KT}$

Hole Emission Rate



# Electron and Hole Capture and Emission

Recombination:

electron capture / hole capture

hole capture / electron capture

Generation:

hole emission / electron emission

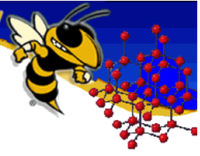
electron emission / hole emission

Recycling of carriers into bands:

hole capture / hole emission

electron capture / electron emission

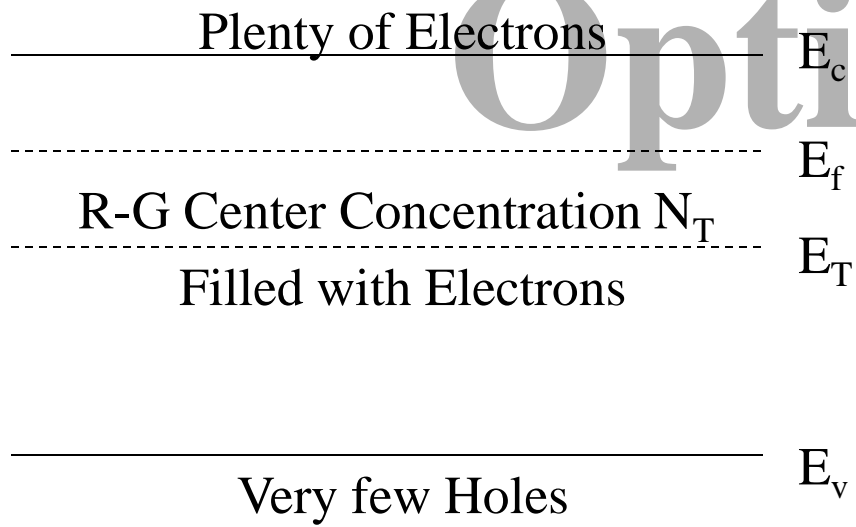
Optional

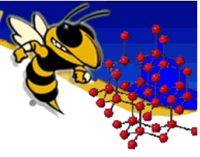


# Carrier Concentrations after a “Perturbation”

$$\left. \frac{\partial p}{\partial t} \right|_{\text{Recombination}} = -c_p N_T p \quad \text{and} \quad \left. \frac{\partial p}{\partial t} \right|_{\text{Generation}} = c_p N_T p_o$$

Optional





# Electron and Hole Capture and Emission

In steady state non-equilibrium, the number of electrons and holes are constant:

$$G - (c_e - e_e) = dn/dt = 0$$

$$G - (c_p - e_p) = dp/dt = 0$$

⑧ The net recombination/generation rate is,

Optional

This equation can be used to solve for  $f'(E)$ , the non-equilibrium fermi distribution function (which does NOT equal  $f(E)$ ), then calculated as,